PATENT

UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Youping Deng et al.	Docket No:	HSJ9-2003-0179US1
Serial No:	New Patent Application	Group Art Unit:	Unassigned
Filed:	Herewith	Examiner:	Unassigned

For: **"HDD YIELD/QUALITY IMPROVEMENT USING CALCULATED FAILURE RATE DERIVED FROM MULTIPLE COMPONENT LEVEL PARAMETERS"**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicant submits herewith the references listed on the attached form PTO-1449 of which Applicant is aware which are believed to be material to the examination of this application and in respect of which there may be a duty to disclose in accordance with 37 CFR 1.56.

The filing of this information disclosure statement shall not be construed as a representation that a search has been made (37 CFR 1.97(g)), nor as an admission that the information cited is, or is considered to be, material to patentability, nor an admission that no other material information exists.

The filing of this information disclosure statement shall not be construed as an admission against interest in any manner. Notice of January 9, 1992, 1135 O.G. 13-25, at 25.

Respectfully submitted,

DATE: September 30, 2003

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CERTIFICATE OF MAILING (37 CFR 1.10(A))

CERTIFICATE OF MAILING BY "EXPRESS MAIL" - Rule 10: I hereby certify that this correspondence is being deposited with the U. S. Postal Service "Express Mail Post Office to Addressee" under 37 CFR 1.10 as Express Mail No. EV326958937US addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on September 30, 2003 by Patricia Beilmann.

Date: September 30, 2003 Patricia Beil

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO.	SERIAL NO.
	HSJ9-2003-0179US1	Unassigned
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	APPLICANT	
	Youping Deng, et al.	
	FILING DATE	GROUP
	Herewith	Unassigned

U. S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	4,841,456	06/20/1989	Hogan, Jr., et al.	364	550	
	AB	5,978,751	11/02/1990	Pence et al.	702	179	
	AC	5,903,460	05/11/1999	Syouji et al.	364	468.24	
	AD	US 6,546,355 B2	04/08/2003	Matsushita	702	152	
	AE	US 6,574,754 B1	06/03/2003	Smith	714	47	
	AF	US 2003/0120445 A1	06/26/2003	Barbour et al.	702	81	
	AG	US 2003/0120457 A1	06/26/2003	Singh et al.	702	181	
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUBCLASS	TRANSLATION YES NO
	AL	JP7198553	08/01/1995	JP	Hitachi Ltd			
	AM	JP4283647	10/08/1992	JP	Hitachi Ltd			
	AN	JP200210015	04/05/2002	JP	Hitachi Ltd			
	AO	JP2001291218	10/19/2001	JP	Hitachi Ltd			
	AP	JP2002319258	10/31/2002	JP	Matsushita Electric			
	AQ	JP2003006809	1/10/2003	JP	Hitachi Ltd			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR		Predicting Defects in Disk Drive Manufacturing: A Case Study in High-Dimensional Classification, C. Apte, S.M. Weiss, and g. Grout, IEEE Annual Conference on AI Applications, CAIA-93, March 1993
	AS		

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.